Book Review

Advances in X-Ray Analysis, Vol. 26, Edited by C. R. Hubbard, C. S. Barrett, P. K. Predecki and D. E. Leyden, Plenum Press, New York, 1984, US$ 49.50, xv + 473 pp.

This volume constitutes the proceedings of the 1982 Denver Conference on the applications of X-ray Analysis. It is divided into 8 sections, 5 of them concerning X-ray diffraction, while the other 3 deal with X-ray fluorescence analysis. Many scientists from various countries have given valuable contributions to the proceedings. Although the main goal of the book, as well of the preceding volumes, is to point out the applications of various methodologies to problems of daily practice, the basic theoretical concepts are also frequently recalled. The major theme discussed is the accuracy in powder diffraction.

Within this topic, the subject of X-ray profile fitting has been considered by many investigators. Extensive studies are reported about the best shape of profiles to be used in conjunction with structure refinement and their impact on the final parameters of physical meaning.

The level of the papers is excellent and allows a broad series of extensions for further applications. This volume is recommended to everyone who wish to stay current with the X-ray field.

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